

PATENT APPLICATION DOCKET NO. 10007804-1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT:

Huei Pei Kuo, et. al.

SERIAL NO.:

10/656,635

FILED:

September 4, 2003

FOR:

ANODIZING PROCESS FOR IMPROVING ELECTRONIC

EMISSION IN ELECTRONIC

DEVICES

ART UNIT:

2811

EXAMINER:

Hu, Shouxiang.

DOCKET NO.:

10007804-1

CERTIFICATE OF DEPOSIT UNDER

37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail, postage prepaid, under 37 C.F.R. § 1.8 on the date indicated below and is addressed to Commissioner for Patents, Alexandria, VA 22313-1450.

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<u>UNDER 37 C.F.R. § 1.131</u>

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

I, Huei Pei Kuo declare as follows:

- 1. I am a named inventor in the above-captioned application and the subject matter described and claimed therein.
- 2. It is my understanding that various claims in the above-recited patent application have been rejected in view of United States Patent Application Publication 2003/0143788 A1, filed

HCT LABS

31, 2002.

January 31, 2002, and entitled "Method of Manufacturing an Emitter."

3. The invention as described and claimed in the above-referenced United States Patent Application Serial Number 10/656,635 was conceived and reduced to practice prior to January 31, 2002. I participated in the development of the claimed fabrication methods and electron emission devices and contributed to the disclosures which were subsequently used in preparation of the above-referenced patent application. Exhibit 1 contains a redacted version of the invention disclosures documenting the conception of the invention, which I prepared and had witnessed prior to January

5. I declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful, false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful, false statement may jeopardize the validity of the application or any patent issuing thereon.

DATED this <u>/&</u> day of May, 2005.

Huei-Pei Kuo, Inventor of the Invention

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EXHIBIT 1

HEWLETT*

Write in dark ink on front side only please? INVENTION DISCLOSURE

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PAGE ONE OF 4

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Was a descrip	tion of the invention published,	or are you planning to publish?	If so, the date(s) and publica	tion(s):	
Was a product	including the invention annour	nced, offered for sale, sold, or is	such activity proposed? If so	, the date(s) an	d location(s):
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was the inven	tion described in a lab book or o	other record? If so, please ident	ify (lab book #, etc.)		
Was the invent	ion built or tested? If so, the da	ate.			
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Was this inven	tion made under a government	contract? If so, the agency and	d contract number:		
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	be signed and dated	I by the inventor(s) and witness	(es).		
A. PriorB. Probl	solutions and their disadvantag	ges (if available, attach copies of	of product literature, technical	articles, patents	s, etc.).
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 D. Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; graphs; flowcharts; computer listings; test results; etc.) 					
Signature of Ir	eventor(s): Pursuant to my (ou	ur) employment agreement, I (w	(e) submit this disclosure on the	nis date: [1
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Employee No.	Name	Signature	Telnet	Mailstop	Entity & Lab Name
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mployee No.	Name	Signature	Telnet	Mailstop	Entity & Lab Name
	ur more than four inventors, in	clude additional information on	another copy of this form and	attach to this d	locument)

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HEWLETT INVENTION DISCLOSURE	COMPANY CONFIDENTIAL	PAGE 2 OF 4
Signature of Witness(es): (Please try to obtain the signature of the p	erson(s) to whom invention was first disclosed.)	
The invention was first explained to, and understood by,	me (us) on this date: []
Full Name Signature	1 11	Date of Signature
STEVEN LOUIS NABERHUIS F Full Name Signature	Steen 2. Makeshin	Oct. 16, 2000
Full Name Signature	/	Date of Signature
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Inventor & Home Address Information: (If more than four inv	entors, include addl. information on a copy of this form b	attach to this document)
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Description of Invention: Please preserve all records of the invention and attach additional pages for the following. Each additional page should be signed and dated by the inventor(s) and witness(es).

A. Prior solutions and their disadvantages (if available, attach copies of product literature, technical articles, patents, etc.).

As dielectric layer is used to delineate the regions to be anodized in porous silicon emitters. An abover The electric field is intensified at the boundry of the dielectric mask. This cause the anodization process to accelerate along the boundary of the mask and causes non-uniform anodization

B. Problems solved by the invention.

The non uniform anodization is minimized when on metallic or conductive material, e.g., chrome, gold, platinum, is used as the anodization mask.

C. Advantages of the invention over what has been done before.

A more uniform anadization and improved electron emission from the anodized area.

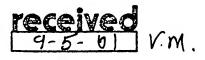
Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; graphs; flowcharts; computer listings; test results; etc.)

To achieve anodization of porous silicon amitters, a metallic mask is used to delineate the intended region to be anodized the field distribution is depicted in the attached diagram.

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INVENTION DISCLOSURE

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Please preserve all records of the invention and attach additional pages for the following. Each additional page should Description of Invention: be signed and dated by the inventor(s) and witness(es).

Prior solutions and their disadvantages (if available, attach copies of product literature, technical articles, patents, etc.).

Electron sources from flat emission surfaces are used for various applications. A patterned dielectric layer is formed on top of the electron source to confine the electron emission to specific regions where no dielectric layer is present. The boundary lines of the dielectric layer, however, lend to have a higher electric field. This causes the electron source to emit preferentially along the border of the emission area and causes device failure along the borders.

B. Problems solved by the invention.

The high field concentration along the border of the electron emission regions is eliminated.

C. Advantages of the invention over what has been done before.

The elimination of the higher field improves the uniformity of the electron emission and improved the life time and stability of electron emission.

Description of the construction and operation of the invention (include appropriate schematic, block, & timing diagrams; drawings; samples; graphs; flowcharts; computer listings; test results; etc.)

The fabrication process of the electron source is depicted in the following figures.

In prior art the following three steps are used to define the emission area.

Figure 1P. A thin layer of polycrystalline silicon is grown on top of single crystalline silicon.

Figure 2P. Prior Art. A layer of dielectric material, e.g. SiO2 or Si3N4, is grown or deposited.

Figure 3P. Prior art. The dielectric layer is patterned to define the emission area.

in the present invention, the following steps are used.

Figure 11. A layer of dielectric material, e.g. SiO2 or Si3N4, is grown or deposited.

Figure 21. The dielectric layer is patterned to define the emission area.

Figure 3I. A thin layer of polycrystalline silicon is grown on top of the single crystalline silicon and the dielectric.

In both the prior art and the present invention

Figure 4. Dielectric layer grown over the structure. When the thermal oxidation is used for this step, a high field along the boarder for the devices is produced with the prior art. The high field is eliminated with the present invention.

Fig 1 P	Present Invention Fig 1i
Poly crystalline silicon (poly) single Crystal silicon (c-si)	dielectric c-si
Tig 2P dielectric Poly	Figai
C-S.	Fig & i
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